

Quasi in-situ SFM nanotomography as a powerful tool for understanding complex morphologies in thin polymer films

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Quasi in-situ SFM imaging



- Low pressure plasma technology as superior ablation method to remove even sensitive material step-by-step
- Straightforward calibration and nanotomographic examination inside the SFM (no time-consuming re-location protocols)
- Mechanical property mapping by SFM TappingMode™ imaging (or other SFM-modes like HarmoniX™) without significant stress to the sample (other methods are normally restricted to intensity-only mapping)
- Compatibility with commercial SFMs; here a retrofitted NanoScope® IV system (Veeco Instruments Inc.)
- Data acquisition time roughly determined by the time needed to scan a image series
- QIS-technique has full automation capabilities
- Flexible patented technology (DE 102004043191 B4 and U.S. patent application 20080229812 A1)

Post-processing

- Registration and combination of topography data $z_n(x,y)$ and phase data $\phi_n(x,y)$ (material property) to a 3D image Φ , by self-developed C++ software package and bash scripting
- General voxelization algorithm works also for non-linear etch behavior: In contrast to the algorithm found in literature where Φ_n is sampled at the points $[x,y,z_n(x,y)-n \cdot \Delta z]$ spanning a regular mesh within the specimen (Magerle, R., Phys. Rev. Lett. 85, 2749, 2000), here a optimized algorithm takes into account possible non-linear etch behavior. The assumed constant thickness of a removed layer Δz is replaced by an etch-time dependent ablation function $a(t)$
- The material-specific ablation function $a(t)$ is based on high-quality QIS-SFM calibration data sets and can be derived from film thickness differences $(D_n - D_0)$ vs. etch time plots (not shown here)
- The displayed isosurfaces enclose all parts of a volume that are brighter than a specific threshold value. This can be interpreted as specific materials in the volume.
- Visualization of the 3D raw data and further processing with commercial 3D software, AMIRA, Visage Imaging Inc., USA
- Inherent high depth-resolution (<1 nm) because the z-coordinate is calculated from SFM-data and high-resolution depth profiling using low pressure plasma

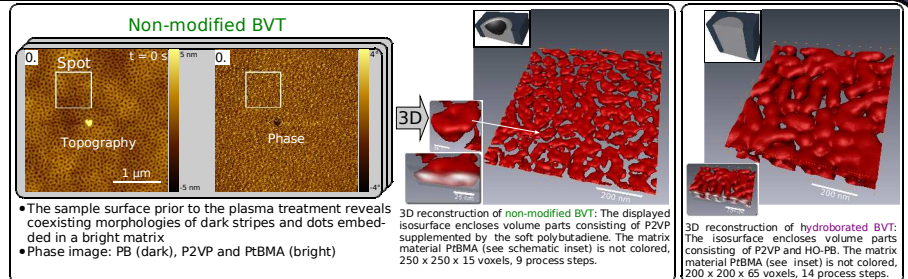
$$\Phi_n[x, y, z_n(x, y) + a(t_n)] \text{ with } a(t_n) \leq 0$$

References: Hund et al., Rev. Sci. Instrum., **78**, 063703 (2007), Olszowka et al., Soft Matter, **2**, 1089 (2006) and Olszowka et al., ACS Nano, **3**, 1091 (2009).

Microphase separation in terblock copolymer^(a)

- **Non-modified BVT:** Asymmetric three component perforated lamella
- **Hydroborated BVT:** Column-like structure and channel-like microphase separated structure suitable for membrane technology
- Imaging techniques like electron tomography do not work because the electron beam destroys the sensitive material

^(a)BVT: 14 wt% polybutadiene (PB), 18 wt% poly(2-vinyl pyridine) (P2VP) and 68 wt% poly(*tert*-butyl methacrylate) (PtBMA), $M_w = 165$ kg/mol

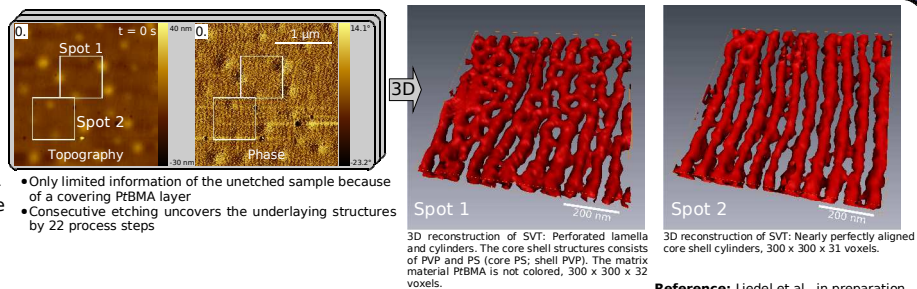


Reference: Sperschneider et al., submitted.

Alignment of a cylindrical terpolymer^(b)

- Microphase separated pattern of SVT has been aligned by simultaneously treatment by solvent vapor under a high electric field (time-resolved QIS-SFM study)
- Experimental evidence for coexistence of perforated lamellar and cylindrical phase in aligned SVT polymer
- SVT is difficult to study with techniques like SEM or electron tomography because of the destructive effect of the electron beam

^(b)SVT: 16 wt% polystyrene (PS), 21 wt% poly(2-vinyl pyridine) (P2VP) and 63 wt% poly(*tert*-butyl methacrylate) (PtBMA), $M_w = 140$ kg/mol

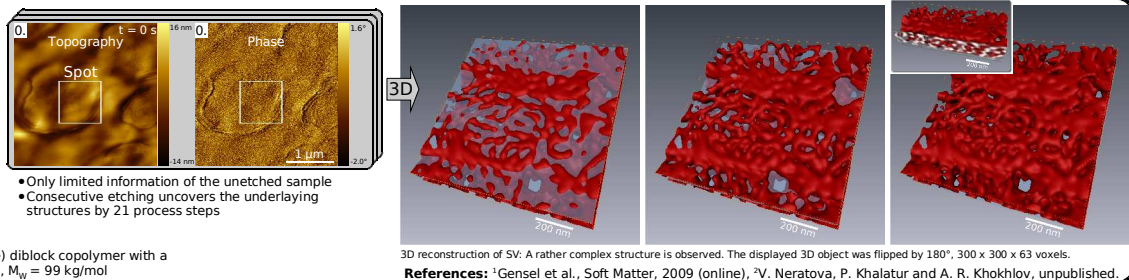


Reference: Liedel et al., in preparation.

Lamella diblock copolymer film^(c)

- Complex combination of lying and up-standing lamella is discovered¹
- Dissipative Brownian dynamic simulations confirm the gained structures²

^(c)SV: Polystyrene-*block*-poly(2-vinyl pyridine) diblock copolymer with a volume fraction of polystyrene (PS) of 0.56, $M_w = 99$ kg/mol

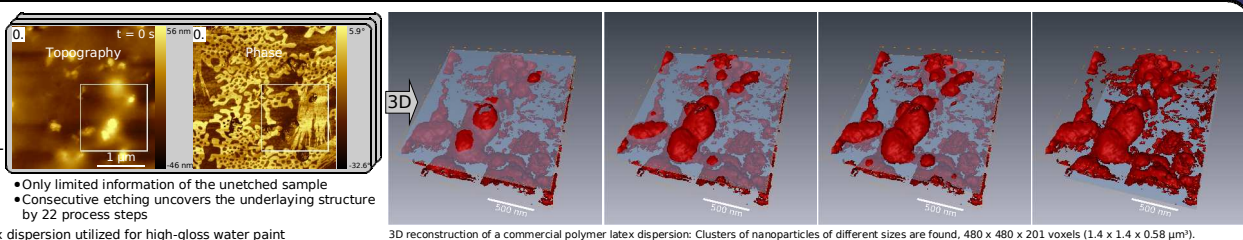


References: Gensel et al., Soft Matter, 2009 (online), V. Nematova, P. Khalatur and A. R. Khokhlov, unpublished.

Latex dispersion^(d)

- Classical x-ray diffraction makes problems by semi-crystalline and non-ordered samples

^(d)Commercial polymer latex dispersion utilized for high-gloss water paint



Conclusions

- The unique QIS-SFM technology makes the world of 3D-imaging accessible for the scanning probe microscopist
- Excellent reliability, high sample throughput and reasonable acquisition times
- Outstanding depth resolution due to unique combination of the SFM instrumentation with plasma technology